

### **Amendments to the Claims**

This listing of the claims replaces all prior versions, and listings, of the claims in the application.

### **Listing of Claims:**

1. (Currently amended) An apparatus for testing an integrated circuit of a device under test by monitoring an analog signal and a digital signal outputted from the integrated circuit, comprising:

a comparator,

a memory for receiving an output signal from said comparator,

a driver for receiving an output signal from said memory,

an adder or subtractor ~~which may that~~ accepts the an analog signal outputted from the integrated circuit and, selectively, a the signal outputted from said memory,

an integrator which accepts an analog signal outputted from said adder or subtractor,

a first switch for selectively transmitting an analog signal outputted from said integrator and ~~a the~~ digital signal outputted from said integrated circuit to said comparator, and

a second switch for selectively transmitting ~~a the~~ signal outputted from said memory and ~~a signal the~~ outputted signal from said comparator to said driver, wherein at least one of said switches is operated depending on whether a signal to be tested is analog or digital.

2. (Previously amended) An apparatus according to claim 1, further comprising a third switch and a digital filter which are connected between said comparator and said memory, for transmitting the signal outputted from said comparator selectively via said digital filter to said memory.

3. (Previously amended) An apparatus according to claim 1, further comprising a delay circuit connected between said comparator and said adder or said subtractor.